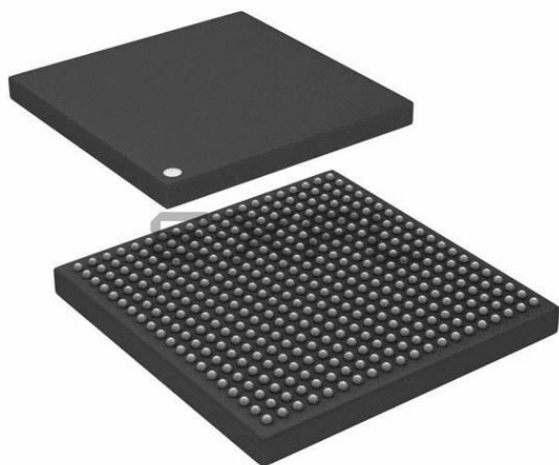




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Understanding [Embedded - DSP \(Digital Signal Processors\)](#)

[Embedded - DSP \(Digital Signal Processors\)](#) are specialized microprocessors designed to perform complex mathematical computations on digital signals in real-time. Unlike general-purpose processors, DSPs are optimized for high-speed numeric processing tasks, making them ideal for applications that require efficient and precise manipulation of digital data. These processors are fundamental in converting and processing signals in various forms, including audio, video, and communication signals, ensuring that data is accurately interpreted and utilized in embedded systems.

Applications of [Embedded - DSP \(Digital Signal Processors\)](#)

Details

Product Status	Obsolete
Type	SC1400 Core
Interface	Host Interface, I ² C, UART
Clock Rate	266MHz
Non-Volatile Memory	External
On-Chip RAM	400kB
Voltage - I/O	3.30V
Voltage - Core	1.20V
Operating Temperature	-40°C ~ 105°C (TJ)
Mounting Type	Surface Mount
Package / Case	400-LFBGA
Supplier Device Package	400-LFBGA (17x17)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/msc7115vf1000

Table of Contents

1	Pin Assignments	4
1.1	MAP-BGA Ball Layout Diagrams	4
1.2	Signal List By Ball Location	6
2	Specifications	17
2.1	Maximum Ratings	17
2.2	Recommended Operating Conditions	18
2.3	Thermal Characteristics	18
2.4	DC Electrical Characteristics	19
2.5	AC Timings	20
3	Hardware Design Considerations	38
3.1	Thermal Design Considerations	38
3.2	Power Supply Design Considerations	39
3.3	Estimated Power Usage Calculations	46
3.4	Reset and Boot	48
3.5	DDR Memory System Guidelines	50
4	Ordering Information	53
5	Package Information	54
6	Product Documentation	54
7	Revision History	55

List of Figures

Figure 1.	MSC7115 Block Diagram	3
Figure 2.	MSC7115 Molded Array Process-Ball Grid Array (MAP-BGA), Top View	4
Figure 3.	MSC7115 Molded Array Process-Ball Grid Array (MAP-BGA), Bottom View	5
Figure 4.	Timing Diagram for a Reset Configuration Write	24
Figure 5.	DDR DRAM Input Timing Diagram	24

Figure 6.	DDR DRAM Output Timing Diagram	26
Figure 7.	DDR DRAM AC Test Load	26
Figure 8.	TDM Receive Signals	27
Figure 9.	TDM Transmit Signals	27
Figure 10.	Read Timing Diagram, Single Data Strobe	29
Figure 11.	Read Timing Diagram, Double Data Strobe	30
Figure 12.	Write Timing Diagram, Single Data Strobe	30
Figure 13.	Write Timing Diagram, Double Data Strobe	31
Figure 14.	Host DMA Read Timing Diagram, HPCR[OAD] = 0	31
Figure 15.	Host DMA Write Timing Diagram, HPCR[OAD] = 0	32
Figure 16.	I2C Timing Diagram	33
Figure 17.	UART Input Timing	34
Figure 18.	UART Output Timing	34
Figure 19.	EE Pin Timing	34
Figure 20.	EVNT Pin Timing	35
Figure 21.	GPI/GPO Pin Timing	35
Figure 22.	Test Clock Input Timing Diagram	36
Figure 23.	Boundary Scan (JTAG) Timing Diagram	37
Figure 24.	Test Access Port Timing Diagram	37
Figure 25.	TRST Timing Diagram	37
Figure 26.	Voltage Sequencing Case 1	40
Figure 27.	Voltage Sequencing Case 2	41
Figure 28.	Voltage Sequencing Case 3	42
Figure 29.	Voltage Sequencing Case 4	43
Figure 30.	Voltage Sequencing Case 5	44
Figure 31.	PLL Power Supply Filter Circuits	45
Figure 32.	SSTL Termination Techniques	50
Figure 33.	SSTL Power Value	51

1 Pin Assignments

This section includes diagrams of the MSC7115 package ball grid array layouts and pinout allocation tables.

1.1 MAP-BGA Ball Layout Diagrams

Top and bottom views of the MAP-BGA package are shown in **Figure 2** and **Figure 3** with their ball location index numbers.

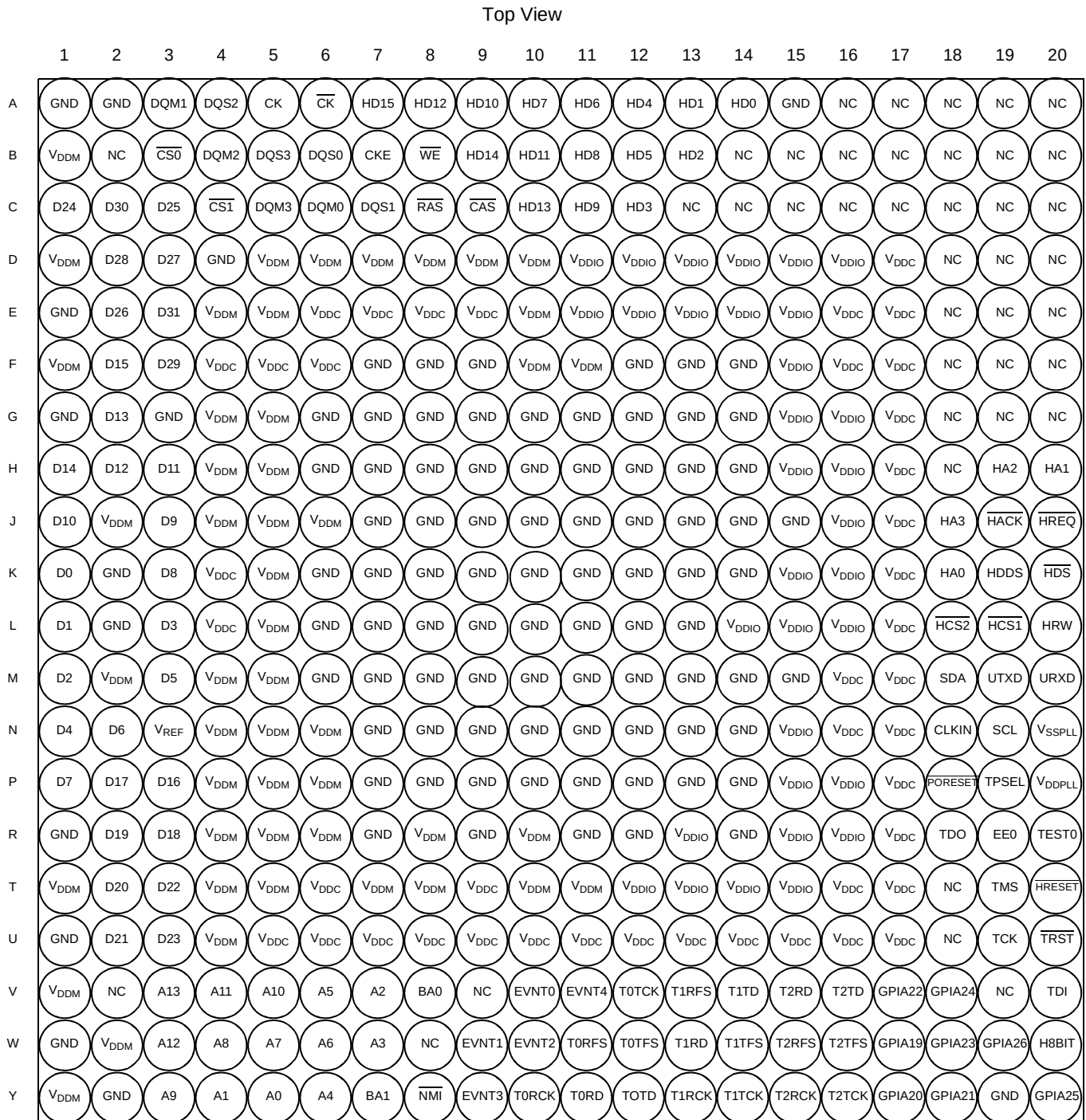


Figure 2. MSC7115 Molded Array Process-Ball Grid Array (MAP-BGA), Top View

Bottom View

	20	19	18	17	16	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1
A	NC	NC	NC	NC	NC	GND	HD0	HD1	HD4	HD6	HD7	HD10	HD12	HD15	$\overline{\text{CK}}$	CK	DQS2	DQM1	GND	GND
B	NC	NC	NC	NC	NC	NC	NC	HD2	HD5	HD8	HD11	HD14	$\overline{\text{WE}}$	CKE	DQS0	DQS3	DQM2	$\overline{\text{CS0}}$	NC	V _{DDM}
C	NC	NC	NC	NC	NC	NC	NC	NC	HD3	HD9	HD13	$\overline{\text{CAS}}$	$\overline{\text{RAS}}$	DQS1	DQM0	DQM3	$\overline{\text{CS1}}$	D25	D30	D24
D	NC	NC	NC	V _{DD}	V _{DDIO}	V _{DDIO}	V _{DDIO}	V _{DDIO}	V _{DDIO}	V _{DDIO}	V _{DDM}	V _{DDM}	V _{DDM}	V _{DDM}	V _{DDM}	V _{DDM}	GND	D27	D28	V _{DDM}
E	NC	NC	NC	V _{DD}	V _{DD}	V _{DDIO}	V _{DDIO}	V _{DDIO}	V _{DDIO}	V _{DDIO}	V _{DDM}	V _{DD}	V _{DD}	V _{DD}	V _{DD}	V _{DDM}	V _{DDM}	D31	D26	GND
F	NC	NC	NC	V _{DD}	V _{DD}	V _{DDIO}	GND	GND	GND	V _{DDM}	V _{DDM}	GND	GND	GND	V _{DD}	V _{DD}	V _{DD}	D29	D15	V _{DDM}
G	NC	NC	NC	V _{DD}	V _{DDIO}	V _{DDIO}	GND	GND	GND	GND	GND	GND	GND	GND	GND	V _{DDM}	V _{DDM}	GND	D13	GND
H	HA1	HA2	NC	V _{DD}	V _{DDIO}	V _{DDIO}	GND	GND	GND	GND	GND	GND	GND	GND	GND	V _{DDM}	V _{DDM}	D11	D12	D14
J	$\overline{\text{HREQ}}$	$\overline{\text{HACK}}$	HA3	V _{DD}	V _{DDIO}	GND	GND	GND	GND	GND	GND	GND	GND	GND	V _{DDM}	V _{DDM}	V _{DDM}	D9	V _{DDM}	D10
K	$\overline{\text{HDS}}$	HDDS	HA0	V _{DD}	V _{DDIO}	V _{DDIO}	GND	GND	GND	GND	GND	GND	GND	GND	GND	V _{DDM}	V _{DD}	D8	GND	D0
L	HRW	$\overline{\text{HCS1}}$	$\overline{\text{HCS2}}$	V _{DD}	V _{DDIO}	V _{DDIO}	V _{DDIO}	GND	GND	GND	GND	GND	GND	GND	GND	V _{DDM}	V _{DD}	D3	GND	D1
M	URXD	UTXD	SDA	V _{DD}	V _{DD}	GND	GND	GND	GND	GND	GND	GND	GND	GND	GND	V _{DDM}	V _{DDM}	D5	V _{DDM}	D2
N	V _{SSPLL}	SCL	CLKIN	V _{DD}	V _{DD}	V _{DDIO}	GND	GND	GND	GND	GND	GND	GND	GND	V _{DDM}	V _{DDM}	V _{DDM}	V _{REF}	D6	D4
P	V _{DDPLL}	TPSEL	$\overline{\text{PORESET}}$	V _{DD}	V _{DDIO}	V _{DDIO}	GND	GND	GND	GND	GND	GND	GND	GND	V _{DDM}	V _{DDM}	V _{DDM}	D16	D17	D7
R	TEST0	EE0	TDO	V _{DD}	V _{DDIO}	V _{DDIO}	GND	V _{DDIO}	GND	GND	V _{DDM}	GND	V _{DDM}	GND	V _{DDM}	V _{DDM}	V _{DDM}	D18	D19	GND
T	$\overline{\text{HRESET}}$	TMS	NC	V _{DD}	V _{DD}	V _{DDIO}	V _{DDIO}	V _{DDIO}	V _{DDIO}	V _{DDM}	V _{DDM}	V _{DD}	V _{DDM}	V _{DDM}	V _{DD}	V _{DDM}	V _{DDM}	D22	D20	V _{DDM}
U	$\overline{\text{TRST}}$	TCK	NC	V _{DD}	V _{DD}	V _{DD}	V _{DD}	V _{DD}	V _{DD}	V _{DD}	V _{DD}	V _{DD}	V _{DD}	V _{DD}	V _{DD}	V _{DD}	V _{DDM}	D23	D21	GND
V	TDI	NC	GPIA24	GPIA22	T2TD	T2RD	T1TD	T1RFS	T0TCK	EVNT4	EVNT0	NC	BA0	A2	A5	A10	A11	A13	NC	V _{DDM}
W	H8BIT	GPIA26	GPIA23	GPIA19	T2TFS	T2RFS	T1TFS	T1RD	T0TFS	T0RFS	EVNT2	EVNT1	NC	A3	A6	A7	A8	A12	V _{DDM}	GND
Y	GPIA25	GND	GPIA21	GPIA20	T2TCK	T2RCK	T1TCK	T1RCK	T0TD	T0RD	T0RCK	EVNT3	$\overline{\text{NMI}}$	BA1	A4	A0	A1	A9	GND	V _{DDM}

Figure 3. MSC7115 Molded Array Process-Ball Grid Array (MAP-BGA), Bottom View

1.2 Signal List By Ball Location

Table 1 lists the signals sorted by ball number and configuration.

Table 1. MSC7115 Signals by Ball Designator

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
A1		GND				
A2		GND				
A3		DQM1				
A4		DQS2				
A5		CK				
A6		$\overline{\text{CK}}$				
A7		GPIC7		GPOC7		HD15
A8		GPIC4		GPOC4		HD12
A9		GPIC2		GPOC2		HD10
A10		reserved				HD7
A11		reserved				HD6
A12		reserved				HD4
A13		reserved				HD1
A14		reserved				HD0
A15		GND				
A16 (1L44X)		NC				
A16 (1M88B)	BM3	GPID8		GPOD7		reserved
A17		NC				
A18		NC				
A19		NC				
A20		NC				
B1		V_{DDM}				
B2		NC				
B3		$\overline{\text{CS0}}$				
B4		DQM2				
B5		DQS3				
B6		DQS0				
B7		CKE				
B8		$\overline{\text{WE}}$				
B9		GPIC6		GPOC6		HD14
B10		GPIC3		GPOC3		HD11
B11		GPIC0		GPOC0		HD8
B12		reserved				HD5
B13		reserved				HD2
B14		NC				
B15 (1L44X)		NC				

Table 1. MSC7115 Signals by Ball Designator (continued)

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
M3						D5
M4						V _{DDM}
M5						V _{DDM}
M6						GND
M7						GND
M8						GND
M9						GND
M10						GND
M11						GND
M12						GND
M13						GND
M14						GND
M15						GND
M16						V _{DDC}
M17						V _{DDC}
M18		GPIA14	$\overline{\text{IRQ15}}$	GPOA14		SDA
M19		GPIA12	$\overline{\text{IRQ3}}$	GPOA12		UTXD
M20		GPIA13	$\overline{\text{IRQ2}}$	GPOA13		URXD
N1						D4
N2						D6
N3						V _{REF}
N4						V _{DDM}
N5						V _{DDM}
N6						V _{DDM}
N7						GND
N8						GND
N9						GND
N10						GND
N11						GND
N12						GND
N13						GND
N14						GND
N15						V _{DDIO}
N16						V _{DDC}
N17						V _{DDC}
N18						CLKIN
N19		GPIA15	$\overline{\text{IRQ14}}$	GPOA15		SCL
N20						V _{SSPLL}

Table 1. MSC7115 Signals by Ball Designator (continued)

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
U17	V _{DDC}					
U18	NC					
U19	TCK					
U20	$\overline{\text{TRST}}$					
V1	V _{DDM}					
V2	NC					
V3	A13					
V4	A11					
V5	A10					
V6	A5					
V7	A2					
V8	BA0					
V9	NC					
V10	reserved				EVNT0	
V11	SWTE	GPIA16	$\overline{\text{IRQ12}}$	GPOA16	EVNT4	
V12	GPIA8		$\overline{\text{IRQ6}}$	GPOA8	T0TCK	
V13	GPIA4		$\overline{\text{IRQ1}}$	GPOA4	T1RFS	
V14	GPIA0		$\overline{\text{IRQ11}}$	GPOA0	T1TD	
V15	GPIA28		$\overline{\text{IRQ17}}$	GPOA28	reserved	T2RD
V16	GPID6			GPOD6	reserved	T2TD
V17	GPIA22		$\overline{\text{IRQ22}}$	GPOA22	reserved	
V18	GPIA24		$\overline{\text{IRQ24}}$	GPOA24	reserved	
V19	NC					
V20	TDI					
W1	GND					
W2	V _{DDM}					
W3	A12					
W4	A8					
W5	A7					
W6	A6					
W7	A3					
W8	NC					
W9	GPIA17		$\overline{\text{IRQ13}}$	GPOA17	EVNT1	CLKO
W10	BM0	GPIC14		GPOC14	EVNT2	
W11	GPIA10		$\overline{\text{IRQ5}}$	GPOA10	T0RFS	
W12	GPIA7		$\overline{\text{IRQ7}}$	GPOA7	T0TFS	
W13	GPIA3		$\overline{\text{IRQ8}}$	GPOA3	T1RD	
W14	GPIA1		$\overline{\text{IRQ10}}$	GPOA1	T1TFS	

Table 1. MSC7115 Signals by Ball Designator (continued)

Number	Signal Names					
	End of Reset	Software Controlled			Hardware Controlled	
		GPI Enabled (Default)	Interrupt Enabled	GPO Enabled	Primary	Alternate
W15	GPID4			GPOD4	reserved	T2RFS
W16	GPIA27		$\overline{\text{IRQ18}}$	GPOA27	reserved	T2TFS
W17	GPIA19		$\overline{\text{IRQ19}}$	GPOA19	reserved	
W18	GPIA23		$\overline{\text{IRQ23}}$	GPOA23	reserved	
W19	GPIA26		$\overline{\text{IRQ26}}$	GPOA26	reserved	
W20	H8BIT	reserved				
Y1	V_{DDM}					
Y2	GND					
Y3	A9					
Y4	A1					
Y5	A0					
Y6	A4					
Y7	BA1					
Y8	reserved		$\overline{\text{NMI}}$	reserved		
Y9	BM1	GPIC15		GPOC15	EVNT3	
Y10	GPIA11		$\overline{\text{IRQ4}}$	GPOA11	T0RCK	
Y11	GPIA9			GPOA9	T0RD	
Y12	GPIA6			GPOA6	T0TD	
Y13	GPIA5		$\overline{\text{IRQ0}}$	GPOA5	T1RCK	
Y14	GPIA2		$\overline{\text{IRQ9}}$	GPOA2	T1TCK	
Y15	GPIA29		$\overline{\text{IRQ16}}$	GPOA29	reserved	T2RCK
Y16	GPID5			GPOD5	reserved	T2TCK
Y17	GPIA20		$\overline{\text{IRQ20}}$	GPOA20	reserved	
Y18	GPIA21		$\overline{\text{IRQ21}}$	GPOA21	reserved	
Y19	GND					
Y20	GPIA25		$\overline{\text{IRQ25}}$	GPOA25	reserved	

2.2 Recommended Operating Conditions

Table 3 lists recommended operating conditions. Proper device operation outside of these conditions is not guaranteed.

Table 3. Recommended Operating Conditions

Rating	Symbol	Value	Unit
Core supply voltage	V_{DDC}	1.14 to 1.26	V
Memory supply voltage	V_{DDM}	2.38 to 2.63	V
PLL supply voltage	V_{DDPLL}	1.14 to 1.26	V
I/O supply voltage	V_{DDIO}	3.14 to 3.47	V
Reference voltage	V_{REF}	1.19 to 1.31	V
Operating temperature range	T_J T_A	maximum: 105 minimum: -40	°C °C

2.3 Thermal Characteristics

Table 4 describes thermal characteristics of the MSC7115 for the MAP-BGA package.

Table 4. Thermal Characteristics for MAP-BGA Package

Characteristic	Symbol	MAP-BGA 17 × 17 mm ⁵		Unit
		Natural Convection	200 ft/min (1 m/s) airflow	
Junction-to-ambient ^{1, 2}	$R_{\theta JA}$	39	31	°C/W
Junction-to-ambient, four-layer board ^{1, 3}	$R_{\theta JA}$	23	20	°C/W
Junction-to-board ⁴	$R_{\theta JB}$	12		°C/W
Junction-to-case ⁵	$R_{\theta JC}$	7		°C/W
Junction-to-package-top ⁶	Ψ_{JT}	2		°C/W
Notes: 1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance. 2. Per SEMI G38-87 and JEDEC JESD51-2 with the single layer board horizontal. 3. Per JEDEC JESD51-6 with the board horizontal. 4. Thermal resistance between the die and the printed circuit board per JEDEC JESD 51-8. Board temperature is measured on the top surface of the board near the package. 5. Thermal resistance between the die and the case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1). 6. Thermal characterization parameter indicating the temperature difference between package top and the junction temperature per JEDEC JESD51-2.				

Section 3.1, *Thermal Design Considerations* explains these characteristics in detail.

2.4 DC Electrical Characteristics

This section describes the DC electrical characteristics for the MSC7115.

Note: The leakage current is measured for nominal voltage values must vary in the same direction (for example, both V_{DDIO} and V_{DDC} vary by +2 percent or both vary by -2 percent).

Table 5. DC Electrical Characteristics

Characteristic	Symbol	Min	Typical	Max	Unit
Core and PLL voltage	V_{DDC} V_{DDPLL}	1.14	1.2	1.26	V
DRAM interface I/O voltage ¹	V_{DDM}	2.375	2.5	2.625	V
I/O voltage	V_{DDIO}	3.135	3.3	3.465	V
DRAM interface I/O reference voltage ²	V_{REF}	$0.49 \times V_{DDM}$	1.25	$0.51 \times V_{DDM}$	V
DRAM interface I/O termination voltage ³	V_{TT}	$V_{REF} - 0.04$	V_{REF}	$V_{REF} + 0.04$	V
Input high CLKIN voltage	V_{IHCLK}	2.4	3.0	3.465	V
DRAM interface input high I/O voltage	V_{IHM}	$V_{REF} + 0.28$	V_{DDM}	$V_{DDM} + 0.3$	V
DRAM interface input low I/O voltage	V_{ILM}	-0.3	GND	$V_{REF} - 0.18$	V
Input leakage current, $V_{IN} = V_{DDIO}$	I_{IN}	-1.0	0.09	1	μA
V_{REF} input leakage current	I_{VREF}	—	—	5	μA
Tri-state (high impedance off state) leakage current, $V_{IN} = V_{DDIO}$	I_{OZ}	-1.0	0.09	1	μA
Signal low input current, $V_{IL} = 0.4$ V	I_L	-1.0	0.09	1	μA
Signal high input current, $V_{IH} = 2.0$ V	I_H	-1.0	0.09	1	μA
Output high voltage, $I_{OH} = -2$ mA, except open drain pins	V_{OH}	2.0	3.0	—	V
Output low voltage, $I_{OL} = 5$ mA	V_{OL}	—	0	0.4	V
Typical core power ⁵ • at 200 MHz • at 266 MHz (mask set 1M88B only)	P_C	— —	222 293	— —	mW mW
Notes: 1. The value of V_{DDM} at the MSC7115 device must remain within 50 mV of V_{DDM} at the DRAM device at all times. 2. V_{REF} must be equal to 50% of V_{DDM} and track V_{DDM} variations as measured at the receiver. Peak-to-peak noise must not exceed $\pm 2\%$ of the DC value. 3. V_{TT} is not applied directly to the MSC7115 device. It is the level measured at the far end signal termination. It should be equal to V_{REF}. This rail should track variations in the DC level of V_{REF}. 4. Output leakage for the memory interface is measured with all outputs disabled, $0 V \leq V_{OUT} \leq V_{DDM}$. 5. The core power values were measured using a standard EFR pattern at typical conditions (25°C, 200 MHz or 266 MHz, 1.2 V core).					

Table 6 lists the DDR DRAM capacitance.

Table 6. DDR DRAM Capacitance

Parameter/Condition	Symbol	Max	Unit
Input/output capacitance: DQ, DQS	C_{IO}	30	pF
Delta input/output capacitance: DQ, DQS	C_{DIO}	30	pF
Note: These values were measured under the following conditions: • $V_{DDM} = 2.5 V \pm 0.125 V$ • $f = 1$ MHz • $T_A = 25^\circ C$ • $V_{OUT} = V_{DDM}/2$ • V_{OUT} (peak to peak) = 0.2 V			

Table 16. Reset Actions for Each Reset Source

Reset Action/Reset Source	Power-On Reset (PORESET)	Hard Reset (HRESET)	Soft Reset (SRESET)
	External only	External or Internal (Software Watchdog or Bus Monitor)	JTAG Command: EXTEST, CLAMP, or HIGHZ
Configuration pins sampled (refer to Section 2.5.3.1 for details).	Yes	No	No
PLL and clock synthesis states Reset	Yes	No	No
HRESET Driven	Yes	Yes	No
Software watchdog and bus time-out monitor registers	Yes	Yes	Yes
Clock synthesis modules (STOPCTRL, HLTREQ, and HLTACK) reset	Yes	Yes	Yes
Extended core reset	Yes	Yes	Yes
Peripheral modules reset	Yes	Yes	Yes

2.5.3.1 Power-On Reset (PORESET) Pin

Asserting $\overline{\text{PORESET}}$ initiates the power-on reset flow. $\overline{\text{PORESET}}$ must be asserted externally for at least 16 CLKIN cycles after external power to the MSC7115 reaches at least $2/3 V_{DD}$.

2.5.3.2 Reset Configuration

The MSC7115 has two mechanisms for writing the reset configuration:

- From a host through the host interface (HDI16)
- From memory through the I²C interface

Five signal levels (see **Chapter 1** for signal description details) are sampled on $\overline{\text{PORESET}}$ deassertion to define the boot and operating conditions:

- BM[0–1]
- SWTE
- H8BIT
- HDSP

2.5.3.3 Reset Timing Tables

Table 17 and **Figure 4** describe the reset timing for a reset configuration write.

Table 17. Timing for a Reset Configuration Write

No.	Characteristics	Expression	Unit
1	Required external $\overline{\text{PORESET}}$ duration minimum	$16/F_{\text{CLKIN}}$	clocks
2	Delay from $\overline{\text{PORESET}}$ deassertion to $\overline{\text{HRESET}}$ deassertion	$521/F_{\text{CLKIN}}$	clocks
Note: Timings are not tested, but are guaranteed by design.			

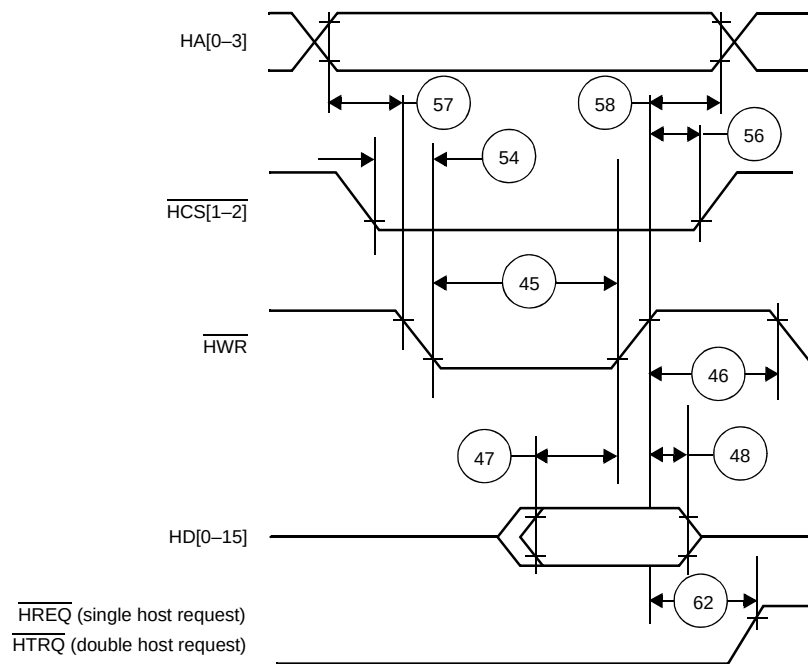


Figure 13. Write Timing Diagram, Double Data Strobe

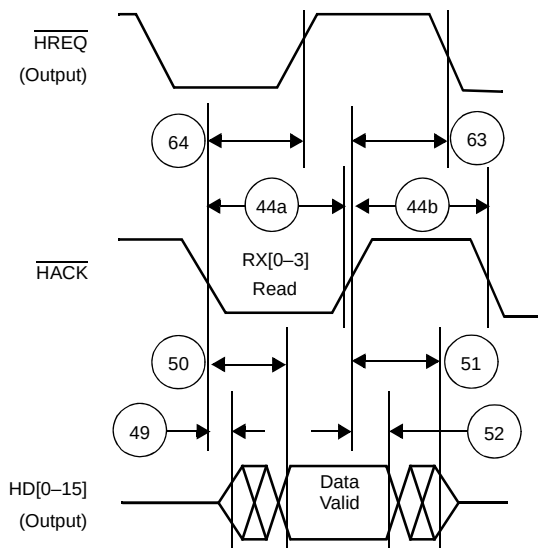


Figure 14. Host DMA Read Timing Diagram, HPCR[OAD] = 0

2.5.10 Event Timing

Table 26. EVNT Signal Timing

Number	Characteristics	Type	Min
67	EVNT as input	Asynchronous	$1.5 \times \text{APBCLK periods}$
68	EVNT as output	Synchronous to core clock	1 APBCLK period
Notes: 1. Refer to Table 24 for a definition of the APBCLK period. 2. Direction of the EVNT signal is configured through the GPIO and Event port registers. 3. Refer to the <i>MSC711x Reference Manual</i> for details on EVNT pin functionality.			

Figure 20 shows the signal behavior of the EVNT pin.

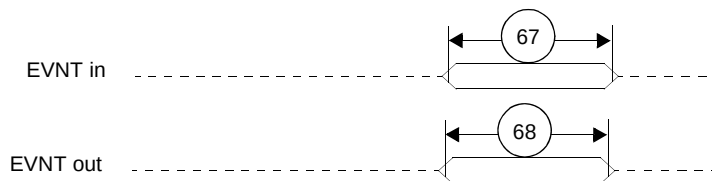


Figure 20. EVNT Pin Timing

2.5.11 GPIO Timing

Table 27. GPIO Signal Timing^{1,2,3}

Number	Characteristics	Type	Min
601	GPI ^{4,5}	Asynchronous	$1.5 \times \text{APBCLK periods}$
602	GPO ⁵	Synchronous to core clock	1 APBCLK period
603	Port A edge-sensitive interrupt	Asynchronous	$1.5 \times \text{APBCLK periods}$
604	Port A level-sensitive interrupt	Asynchronous	$3 \times \text{APBCLK periods}^6$
Notes: 1. Refer to Table 24 for a definition of the APBCLK period. 2. Direction of the GPIO signal is configured through the GPIO port registers. 3. Refer to <i>MSC711x Reference Manual</i> for details on GPIO pin functionality. 4. GPI data is synchronized to the APBCLK internally and the minimum listed is the capability of the hardware to capture data into a register when the GPA_DR is read. The specification is not tested due to the asynchronous nature of the input and dependence on the state of the DSP core. It is guaranteed by design. 5. The input and output signals cannot toggle faster than 50 MHz. 6. Level-sensitive interrupts should be held low until the system determines (via the service routine) that the interrupt is acknowledged.			

Figure 21 shows the signal behavior of the GPI/GPO pin.

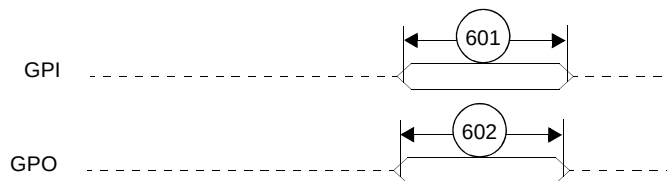


Figure 21. GPI/GPO Pin Timing

2.5.12 JTAG Signals

Table 28. JTAG Timing

No.	Characteristics	All frequencies		Unit
		Min	Max	
700	TCK frequency of operation ($1/(T_C \times 3)$; maximum 22 MHz)	0.0	40.0	MHz
701	TCK cycle time	25.0	—	ns
702	TCK clock pulse width measured at $V_M = 1.6$ V	11.0	—	ns
703	TCK rise and fall times	0.0	3.0	ns
704	Boundary scan input data set-up time	5.0	—	ns
705	Boundary scan input data hold time	14.0	—	ns
706	TCK low to output data valid	0.0	20.0	ns
707	TCK low to output high impedance	0.0	20.0	ns
708	TMS, TDI data set-up time	5.0	—	ns
709	TMS, TDI data hold time	25.0	—	ns
710	TCK low to TDO data valid	0.0	24.0	ns
711	TCK low to TDO high impedance	0.0	10.0	ns
712	$\overline{\text{TRST}}$ assert time	100.0	—	ns
Note: All timings apply to OCE module data transfers as the OCE module uses the JTAG port as an interface.				

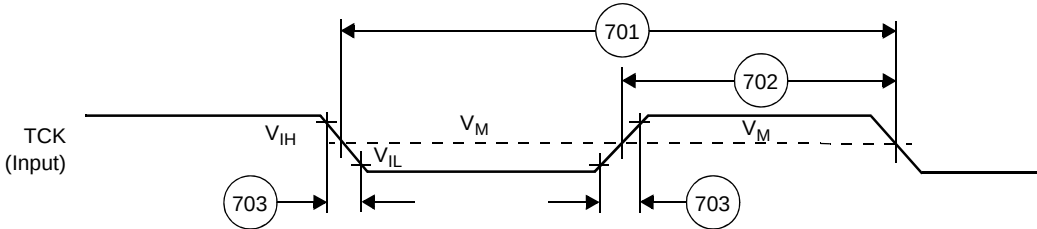


Figure 22. Test Clock Input Timing Diagram

3 Hardware Design Considerations

This section describes various areas to consider when incorporating the MSC7115 device into a system design.

3.1 Thermal Design Considerations

An estimation of the chip-junction temperature, T_J , in °C can be obtained from the following:

$$T_J = T_A + (R_{\theta JA} \times P_D) \quad \text{Eqn. 1}$$

where

T_A = ambient temperature near the package (°C)

$R_{\theta JA}$ = junction-to-ambient thermal resistance (°C/W)

$P_D = P_{INT} + P_{I/O}$ = power dissipation in the package (W)

$P_{INT} = I_{DD} \times V_{DD}$ = internal power dissipation (W)

$P_{I/O}$ = power dissipated from device on output pins (W)

The power dissipation values for the MSC7115 are listed in **Table 4**. The ambient temperature for the device is the air temperature in the immediate vicinity that would cool the device. The junction-to-ambient thermal resistances are JEDEC standard values that provide a quick and easy estimation of thermal performance. There are two values in common usage: the value determined on a single layer board and the value obtained on a board with two planes. The value that more closely approximates a specific application depends on the power dissipated by other components on the printed circuit board (PCB). The value obtained using a single layer board is appropriate for tightly packed PCB configurations. The value obtained using a board with internal planes is more appropriate for boards with low power dissipation (less than 0.02 W/cm² with natural convection) and well separated components. Based on an estimation of junction temperature using this technique, determine whether a more detailed thermal analysis is required. Standard thermal management techniques can be used to maintain the device thermal junction temperature below its maximum. If T_J appears to be too high, either lower the ambient temperature or the power dissipation of the chip.

You can verify the junction temperature by measuring the case temperature using a small diameter thermocouple (40 gauge is recommended) or an infrared temperature sensor on a spot on the device case. Use the following equation to determine T_J :

$$T_J = T_T + (\Psi_{JT} \times P_D) \quad \text{Eqn. 2}$$

where

T_T = thermocouple (or infrared) temperature on top of the package (°C)

Ψ_{JT} = thermal characterization parameter (°C/W)

P_D = power dissipation in the package (W)

3.2.2.5 Case 5 (not recommended for new designs)

The power-up sequence is as follows:

1. Turn on the V_{DDIO} (3.3 V) supply first.
2. Turn on the V_{DDM} (2.5 V) supply second.
3. Turn on the V_{DDC} (1.2 V) supply third.
4. Turn on the V_{REF} (1.25 V) supply fourth (last).

Note: Make sure that the time interval between the ramp-up of V_{DDIO} and V_{DDM} is less than 10 ms.

The power-down sequence is as follows:

1. Turn off the V_{REF} (1.25 V) supply first.
2. Turn off the V_{DDC} (1.2 V) supply second.
3. Turn off the V_{DDM} (2.5 V) supply third.
4. Turn of the V_{DDIO} (3.3 V) supply fourth (last).

Use the following guidelines:

- Make sure that the time interval between the ramp-down of V_{DDIO} and V_{DDM} is less than 10 ms.
- Make sure that the time interval between the ramp-up or ramp-down for V_{DDC} and V_{DDM} is less than 2 ms for power-up and power-down.
- Refer to **Figure 30** for relative timing for power sequencing case 5.

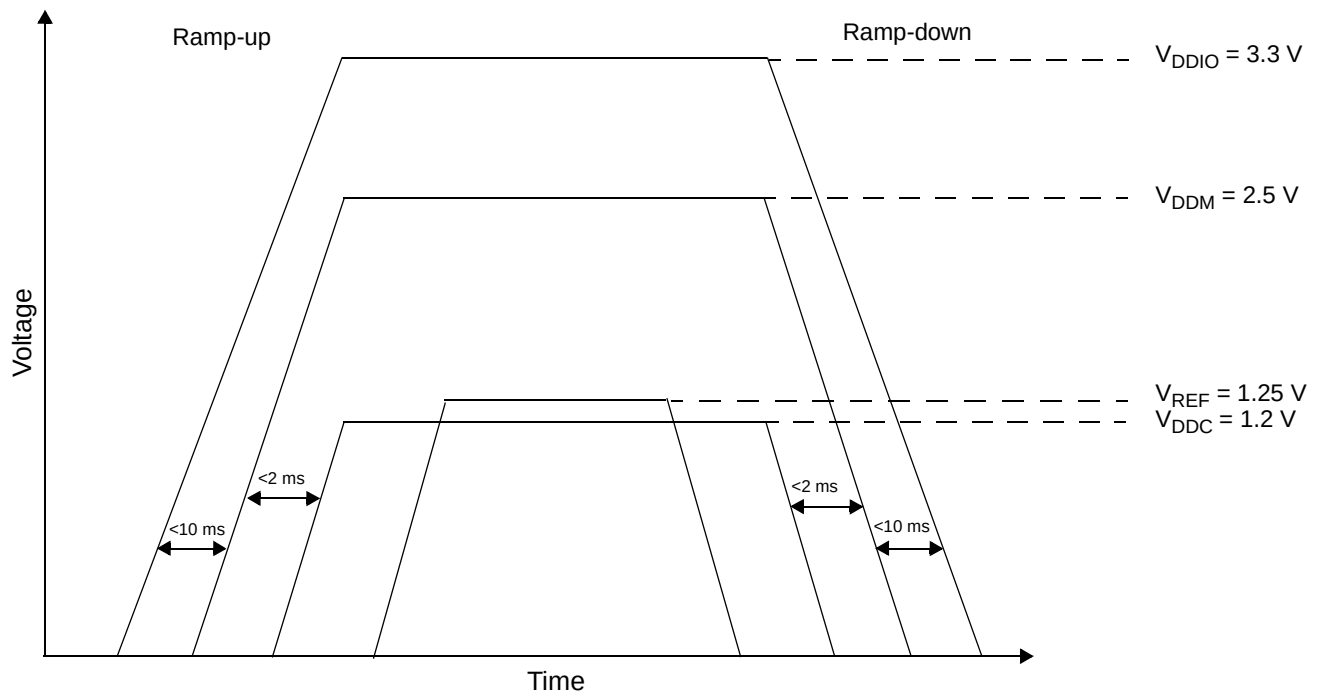


Figure 30. Voltage Sequencing Case 5

Note: Cases 1, 2, 3, and 4 are recommended for system design. Designs that use Case 5 may have large current spikes on the V_{DDM} supply at startup and is not recommended for most designs. If a design uses case 5, it must accommodate the potential current spikes. Verify risks related to current spikes using actual information for the specific application.

3.2.7 Power Supply Design

One of the most common ways to derive power is to use either a simple fixed or adjustable linear regulator. For the system I/O voltage supply, a simple fixed 3.3 V supply can be used. However, a separate adjustable linear regulator supply for the core voltage V_{DDC} should be implemented. For the memory power supply, regulators are available that take care of all DDR power requirements.

Table 30. Recommended Power Supply Ratings

Supply	Symbol	Nominal Voltage	Current Rating
Core	V_{DDC}	1.2 V	1.5 A per device
Memory	V_{DDM}	2.5 V	0.5 A per device
Reference	V_{REF}	1.25 V	10 μ A per device
I/O	V_{DDIO}	3.3 V	1.0 A per device

3.3 Estimated Power Usage Calculations

The following equations permit estimated power usage to be calculated for individual design conditions. Overall power is derived by totaling the power used by each of the major subsystems:

$$P_{TOTAL} = P_{CORE} + P_{PERIPHERALS} + P_{DDRIO} + P_{IO} + P_{LEAKAGE} \quad \text{Eqn. 3}$$

This equation combines dynamic and static power. Dynamic power is determined using the generic equation:

$$C \times V^2 \times F \times 10^{-3} \text{ mW} \quad \text{Eqn. 4}$$

where,

C = load capacitance in pF

V = peak-to-peak voltage swing in V

F = frequency in MHz

3.3.1 Core Power

Estimation of core power is straightforward. It uses the generic dynamic power equation and assumes that the core load capacitance is 750 pF, core voltage swing is 1.2 V, and the core frequency is 200 MHz or 266 MHz. This yields:

$$P_{CORE} = 750 \text{ pF} \times (1.2 \text{ V})^2 \times 200 \text{ MHz} \times 10^{-3} = 216 \text{ mW} \quad \text{Eqn. 5}$$

$$P_{CORE} = 750 \text{ pF} \times (1.2 \text{ V})^2 \times 266 \text{ MHz} \times 10^{-3} = 287 \text{ mW} \quad \text{Eqn. 6}$$

This equation allows for adjustments to voltage and frequency if necessary.

3.3.4 External I/O Power

The estimation of the I/O power is similar to the computation of the peripheral power estimates. The power consumption per signal line is computed assuming a maximum load of 20 pF, a voltage swing of 3.3 V, and a switching frequency of 25 MHz or 33 MHz, which yields:

$$P_{IO} = 20 \text{ pF} \times (3.3 \text{ V})^2 \times 25 \text{ MHz} \times 10^{-3} = 5.44 \text{ mW per I/O line} \quad \text{Eqn. 16}$$

$$P_{IO} = 20 \text{ pF} \times (3.3 \text{ V})^2 \times 33 \text{ MHz} \times 10^{-3} = 7.19 \text{ mW per I/O line} \quad \text{Eqn. 17}$$

Multiply this number by the number of I/O signal lines used in the application design to compute the total I/O power.

Note: The signal loading depends on the board routing. For systems using a single DDR device, the load could be as low as 7 pF.

3.3.5 Leakage Power

The leakage power is for all power supplies combined at a specific temperature. The value is temperature dependent. The observed leakage value at room temperature is 64 mW.

3.3.6 Example Total Power Consumption

Using the examples in this section and assuming four peripherals and 10 I/O lines active, a total power consumption value is estimated as the following:

$$P_{TOTAL} (200 \text{ MHz core}) = 216 + (4 \times 2.88) + 324.2 + (10 \times 5.44) + 64 = 670.12 \text{ mW} \quad \text{Eqn. 18}$$

$$P_{TOTAL} (266 \text{ MHz core}) = 287 + (4 \times 3.83) + 326.3 + (10 \times 7.19) + 64 = 764.52 \text{ mW} \quad \text{Eqn. 19}$$

3.4 Reset and Boot

This section describes the recommendations for configuring the MSC7115 at reset and boot.

3.4.1 Reset Circuit

$\overline{\text{HRESET}}$ is a bidirectional signal and, if driven as an input, should be driven with an open collector or open-drain device. For an open-drain output such as $\overline{\text{HRESET}}$, take care when driving many buffers that implement input bus-hold circuitry. The bus-hold currents can cause enough voltage drop across the pull-up resistor to change the logic level to low. Either a smaller value of pull-up or less current loading from the bus-hold drivers overcomes this issue. To avoid exceeding the MSC7115 output current, the pull-up value should not be too small (a 1 K Ω pull-up resistor is used in the MSC711xADS reference design).

3.4.2 Reset Configuration Pins

Table 31 shows the MSC7115 reset configuration signals. These signals are sampled at the deassertion (rising edge) of $\overline{\text{PORESET}}$. For details, refer to the Reset chapter of the *MSC711x Reference Manual*.

Table 31. Reset Configuration Signals

Signal	Description	Settings
BM[1–0]	Determines boot mode.	0 Boot from HDI16 port. 01 Boot from I ² C. 1x Reserved.
SWTE	Determines watchdog functionality.	0 Watchdog timer disabled. 1 Watchdog timer enabled.
HDSP	Configures HDI16 strobe polarity.	0 Host Data strobes active low. 1 Host Data strobes active high.
H8BIT	Configures HDI16 operation mode.	0 HDI16 port configured for 16-bit operation. 1 HDI16 port configured for 8-bit operation.

3.4.3 Boot

After a power-on reset, the PLL is bypassed and the device is directly clocked from the CLKIN pin. Using this input clock, the system initializes using the boot loader program that resides in the internal ROM. After initialization, the DSP core can enable the PLL and start the device operating at a higher speed. The MSC7115 can boot from an external host through the HDI16 or download a user program through the I²C port. The boot operating mode is set by configuring the BM[1–0] signals sampled at the rising edge of $\overline{\text{PORESET}}$, as shown in **Table 32**.

Table 32. Boot Mode Settings

BM1	BM0	Boot Source
0	0	External host via HDI16 with the PLL disabled.
0	1	I ² C.
1	0	External host via the HDI16 with the PLL enabled.
1	1	Reserved.

3.4.3.1 HDI16 Boot

If the MSC7115 device boots from an external host through the HDI16, the port is configured as follows:

- Operate in Non-DMA mode.
- Operate in polled mode on the device side.
- Operate in polled mode on the external host side.
- External host must write four 16-bit values at a time with the first word as the most significant and the fourth word as the least significant.

When booting from a power-on reset, the HDI16 is additionally configurable as follows:

- 8- or 16-bit mode as specified by the H8BIT pin.
- Data strobe as specified by the HDSP and HDDS pins.

These pins are sampled only on the deassertion of power-on reset. During a boot from a hard reset, the configuration of these pins is unaffected.

Note: When the HDI16 is used for booting or other purposes, bit 0 is the least significant bit and not the most significant bit as for other DSP products.

5 Package Information

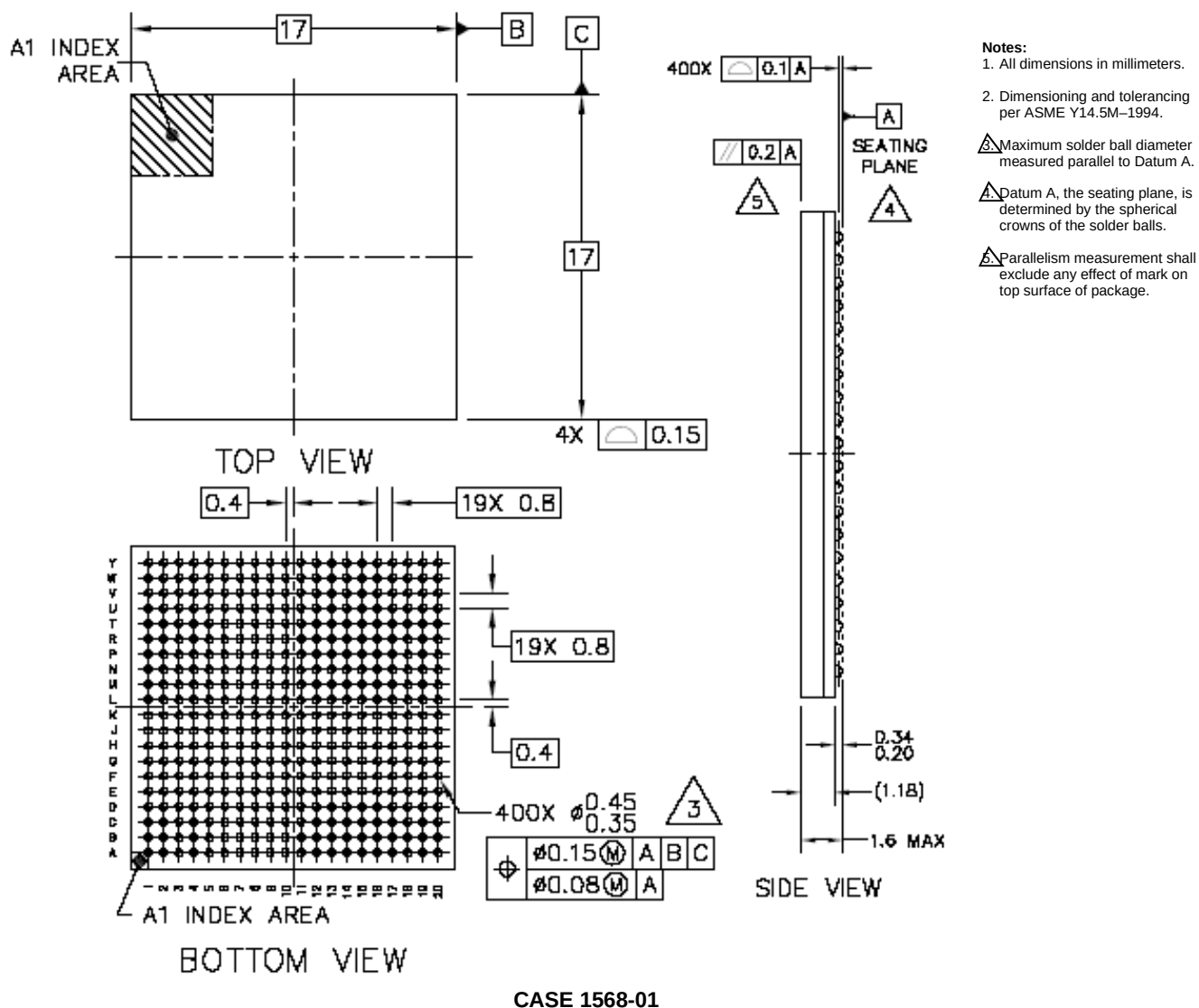


Figure 34. MSC7115 Mechanical Information, 400-pin MAP-BGA Package

6 Product Documentation

- *MSC711x Reference Manual* (MSC711xRM). Includes functional descriptions of the extended cores and all the internal subsystems including configuration and programming information.
- *Application Notes*. Cover various programming topics related to the StarCore DSP core and the MSC7115 device.
- *SC140/SC1400 DSP Core Reference Manual*. Covers the SC140 and SC1400 core architecture, control registers, clock registers, program control, and instruction set.

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